


<b>Search Notes</b>  	<b>Application/Control No.</b>  10588023	<b>Applicant(s)/Patent Under Reexamination</b>  HECKER ET AL.
	<b>Examiner</b>  Hanh Phan	<b>Art Unit</b>  2613

SEARCHED			
Class	Subclass	Date	Examiner
398	183, 184, 185, 186, 188, 192, 195, 196, 197, 198, 79, 65, 152	02/12/20009	HP
385	11, 3, 39	02/12/2009	HP
359	246, 254, 245	02/12/2009	HP

SEARCH NOTES		
Search Notes	Date	Examiner
EAST SEARCH SEE ATTACHED PRINTOUT IN THE FILE	02/12/2009	HP
IEEE SEARCH	02/12/2009	HP
JPO SEARCH	02/12/2009	HP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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